Issue Classification

Application/Control No.	Applicant(s)/Patent Under Reexamination
10686553	WALSH, PATRICK JAY
Examiner	**Art Unit**
David Q Nguyen	2617

ORIGINAL		INTERNATIONAL CLASSIFICATION	
CLASS	SUBCLASS	CLAIMED	NON-CLAIMED
455	456.1	H 0 4 Q 7 / 20 (2006.01.01)	

CROSS REFERENCE(S)

CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)				
455	456.2	456.3	456.6	411	
370	338				

NONE (Assistant Examiner) (Date)		**Total Claims Allowed:** 17
/David Q Nguyen/ (Primary Examiner)	03/05/08 (Date)	O.G. Print Claim(s) 1 / O.G. Print Figure 1